

Search Notes

Application/Control No.

10/689,091

Examiner

Leon J. Harper

Applicant(s)/Patent under
Reexamination

CHANG, YUAN-CHI

Art Unit

2166

SEARCHED

Class	Subclass	Date	Examiner
707	10,13,104. 1,100,101	5/31/2006	LJH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR